Notice of References Cited Application/Control No. 10/723,389 Examiner Dimple N. Bodawala Applicant(s)/Patent Under Reexamination VEARIEL ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,029,474 A	04-1962	HERMANN HOLCH; et. al.	264/209.1
*	В	US-5,192,543 A	03-1993	Irvin et al.	425/378.1
*	С	US-6,409,491 B1	06-2002	Leffew et al.	425/67
	۵	US-			
	Е	US-			
	F	ŲS-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 58217327 A	12-1983	Japan	SHIGEMOTO et al.	B29D 23/03
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	Р					
	Q	·				
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	HON-PATENT BOODINERTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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